FOREWORD

The papers in this and the next special issue were originally presented at the already fourth Seminar on Intelligent Measurement Systems, sponsored by the IEEE Hungary Section (Region 8), held at and organized by the Department of Measurement and Instrument Engineering, Technical University of Budapest, between July 2-4, 1990.

The published papers are the thoroughly corrected, improved and occasionally shortened versions of the Seminar contributions.

This time, beside the already regular participants from Germany, The Netherlands, Belgium and Estonia, we had the pleasure to host guests also from the United Kingdom and France. Also a certain novelty was the organisation of the Student Section, which resulted in really interesting, high quality presentations.

Most of the lectures treated the fields of system testing and advanced signal processing. Several contributions addressed such 'hot' research topics as neural networks, qualitative physics, knowledge-based signal processing etc.

It would not be fair to make any difference among really interesting topics and excellent presentations. It seems however appropriate to mention that Dr. J. S. D. Mason from the University College of Swansea was unanimously applauded for the best lecture read.

We strongly hope that in the year 1992 we will be able to meet again, old and new friends, and discuss what progress time brought into our field of research.

Budapest, December 28, 1990.

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